

Page 16, line 21 through page 17, line 18.

AI Then, a description will be given to the configuration, function, and the like of the beam used in the foregoing method. As described in the paragraph of the prior art, for holding the minute micro-sample by two independent movable beams in accordance with the prior art method, a high precision alignment operation of the movable beam tips is required. In addition, as described previously, unfavorably, the minute micro-sample is difficult to hold with reliability. In contrast, in the present invention, the alignment of the beam tip for holding the micro-sample is essentially unnecessary. Further, it is possible to hold the micro-sample with reliability. As a specific method, the micro-sample sandwiched in the beam tip, and thus extracted from the specimen substrate is inserted and held in the trench for insertion of the micro-sample disposed on the sample holder. Thus, the micro-sample is pulled out of and separated (detached) from the beam. The beam is a beam made up of a rod-like member having a shape in which its tip is formed thinner as compared with its root, and the tip is split into two units. By sandwiching and holding the micro-sample between the beam tip split into two units, the micro-sample is held through the elastic deformation force of the beam tip without using a piezoelectric element or the like.

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AV FIGS. 14H, and 14J to 14N are a schematic flow chart of steps for illustrating a specimen fabrication process by using a specimen fabrication equipment in accordance with a tenth example of the present invention;